

# INTERNATIONAL STANDARD

## NORME INTERNATIONALE

**Fibre optic communication subsystem test procedures – Digital systems –  
Part 2-8: Determination of low BER using Q-factor measurements**

**Procédures d'essai des sous-systèmes de télécommunication à fibres  
optiques – Systèmes numériques –  
Partie 2-8: Détermination de faible Taux d'Erreur Binaire (TEB) en utilisant  
des mesures du facteur Q**



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IEC Central Office  
3, rue de Varembe  
CH-1211 Geneva 20  
Switzerland

Tel.: +41 22 919 02 11  
Fax: +41 22 919 03 00  
[info@iec.ch](mailto:info@iec.ch)  
[www.iec.ch](http://www.iec.ch)

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# INTERNATIONAL ELECTROTECHNICAL COMMISSION

## FIBRE OPTIC COMMUNICATION SUBSYSTEM TEST PROCEDURES – DIGITAL SYSTEMS –

### Part 2-8: Determination of low BER using Q-factor measurements

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86C/485/FDIS	86C/505/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

The French version of this standard has not been voted upon.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

The committee has decided that the contents of this publication will remain unchanged until 2010. At this date, the publication will be

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